

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination BENJAMIN ET AL.	
		Examiner Laura E. Martin	Art Unit 2853	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0175965	11-2002	Skene et al.	347/19
*	B	US-2002/0057305	05-2002	Kao et al.	347/14
*	C	US-2002/0060722	05-2002	Axtell et al.	347/57
*	D	US-6,385,407	05-2002	Inose, Fumiayuki	399/24
*	E	US-5,886,726	03-1999	Pawelka et al.	347/197
*	F	US-5,431,673	07-1995	Summers et al.	606/170
*	G	US-2003/0146967	08-2003	Miller, John R.	347/191
*	H	US-6,081,280	06-2000	Bolash et al.	347/9
*	I	US-2002/0145645	10-2002	Aono et al.	347/48
J	US-				
K	US-				
L	US-				
M	US-				

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1128324 A2	08-2001	European Patent	HAYASAKI, KIMIYUKI	G06K 15/10
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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